

ZXMN2B14FH 20V SOT23 N-channel enhancement mode MOSFET with low gate drive capability

Summary

V _{(BR)DSS}	R _{DS(on)} (Ω)	I _D (A)	
	0.055 @ V _{GS} = 4.5V	4.3	
20	0.075 @ V _{GS} = 2.5V	3.7	
	0.100 @ V _{GS} = 1.8V	3.2	



This new generation of trench MOSFETs from Zetex features low onresistance achievable with low gate drive.

Features

- Low on-resistance
- · Fast switching speed
- · Low gate drive capability
- SOT23 package

Applications

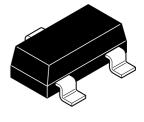
- DC-DC converters
- Power management functions
- Disconnect switches
- Motor control

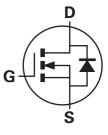
Ordering information

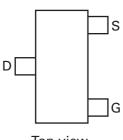
Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN2B14FHTA	7	8	3,000

Device marking

2B4







Top view

Absolute maximum ratings

Parameter	Symbol	Limit	Unit	
Drain-source voltage	V _{DSS}	20	V	
Gate-source voltage	V _{GS}	± 8	V	
Continuous drain current	@ V_{GS} = 4.5V; T_{amb} =25°C (b)	I _D	4.3	А
	@ V_{GS} = 4.5V; T_{amb} =70°C (b)		3.5	
	@ V_{GS}= 4.5V; T_{amb}=25°C (a)		3.5	
Pulsed drain current (c)	I _{DM}	21	А	
Continuous source current	۱ _S	2.4	А	
Pulsed source current (boo	I _{SM}	21	А	
Power dissipation at T _{amb} =	P _D	1	W	
Linear derating factor		8	mW/°C	
Power dissipation at T _{amb}	P _D	1.5	W	
Linear derating factor		12	mW/°C	
Operating and storage terr	T _j , T _{stg}	-55 to +150	°C	

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient	R_{\ThetaJA}	125	°C/W
Junction to ambient	R_{\ThetaJA}	82	°C/W

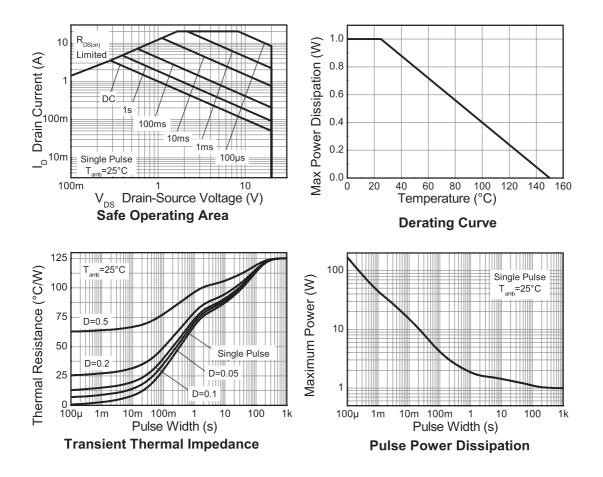
NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on FR4 PCB measured at t ${\leq}5$ sec.

(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width $300\mu s$ - pulse width limited by maximum junction temperature.

Thermal characteristics



Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-source breakdown voltage	V _{(BR)DSS}	20			V	I _D = 250μA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}			1	μA	V _{DS} = 20V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±8V, V _{DS} =0V
Gate-source threshold voltage	V _{GS(th)}	0.4		1.0	V	I _D = 250μA, V _{DS} =V _{GS}
Static drain-source on-state	R _{DS(on)}			0.055	Ω	V _{GS} = 4.5V, I _D = 3.5A
resistance ^(*)				0.075	Ω	V _{GS} = 2.5V, I _D = 3A
				0.100	Ω	V _{GS} = 1.8V, I _D = 2.6A
Forward transconductance ^(*) (‡)	9 _{fs}		11		S	V _{DS} = 10V, I _D = 3.5A
Dynamic ^(‡)						I
Input capacitance	C _{iss}		872		pF	V _{DS} = 10V, V _{GS} =0V
Output capacitance	C _{oss}		145		pF	f=1MHz
Reverse transfer capacitance	C _{rss}		90		pF	•
Switching ^{(†) (‡)}						I
Turn-on-delay time	t _{d(on)}		3.7		ns	V _{DD} = 10V, V _{GS} = 4.5V
Rise time	t _r		5.2		ns	I _D = 1A
Turn-off delay time	t _{d(off)}		30		ns	$R_{G} \approx 6.0\Omega$
Fall time	t _f		5.5		ns	•
Total gate charge	Qg		11		nC	V _{DS} = 10V, V _{GS} = 4.5V
Gate-source charge	O _{gs}		1.4		nC	I _D = 4.0A
Gate drain charge	Q _{gd}		2.1		nC	
Source-drain diode		1	L			1
Diode forward voltage ^(*)	V _{SD}		0.69	0.95	V	T _j =25°C, I _S = 1.45A, V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		9.4		ns	T _j =25°C, I _F = 2.4A,
Reverse recovery charge ^(‡)	Q _{rr}	1	2.8		nC	di/dt=100A/µs

Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

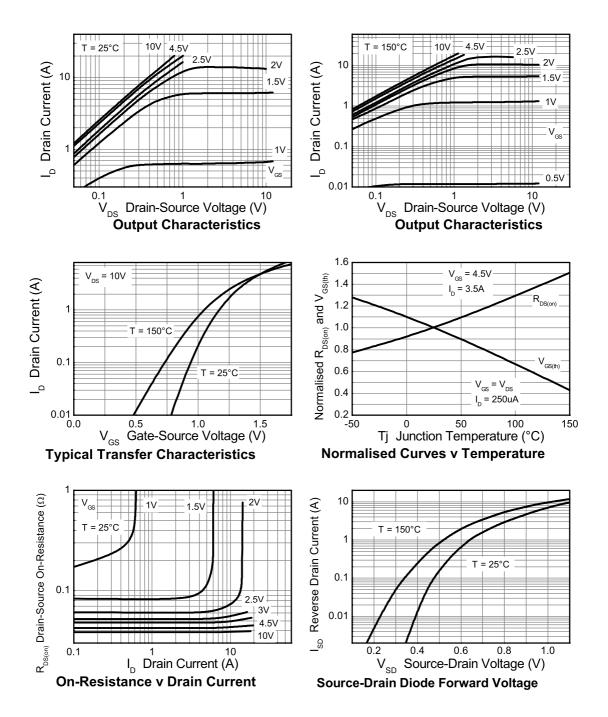
NOTES:

(*) Measured under pulsed conditions. Pulse width ${\leq}300\mu s;$ duty cycle ${\leq}2\%.$

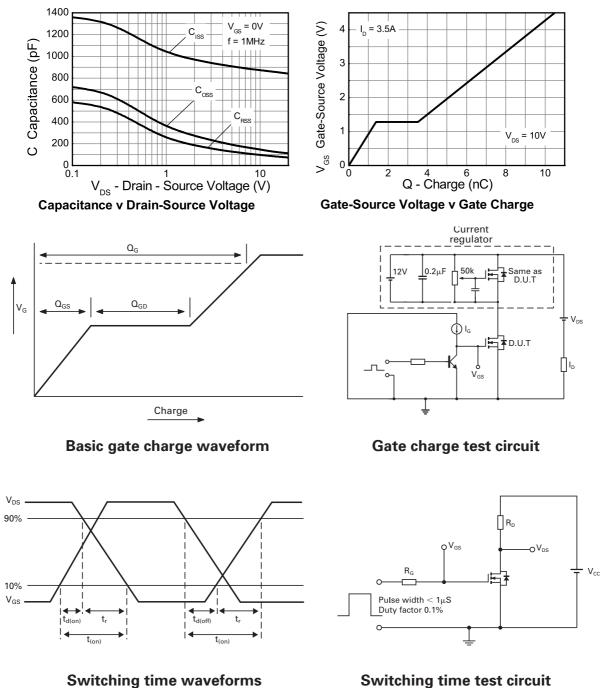
(†) Switching characteristics are independent of operating junction temperature.

(‡) For design aid only, not subject to production testing.

Typical characteristics

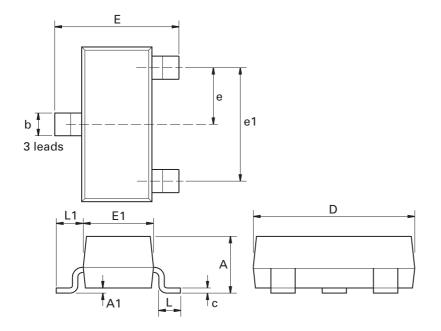


Typical characteristics



Switching time test circuit

Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Max.	Max.
А	-	1.12	-	0.044	e1	1.90	NOM	0.075	NOM
A1	0.01	0.10	0.0004	0.004	E	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.120	0.003	0.008	L	0.25	0.62	0.018	0.024
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.0375	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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